SIDIS PID Performance Updates

11/30/2017

Previous Issues

With current simulated backgrounds, PID performance from both FAEC and LAEC are worse than PcDR results.

FAEC PID Cuts Efficiency



LAEC PID Cuts Efficiency











Summary and Outlook

- Including the current SIDIS simulated backgrounds, PID performance (e/π- separation) from both FAEC and LAEC are consistent with PcDR results (Jing's results) (by ignoring the edge effect)
- For low momentum (p<1GeV/c) events, electron efficiency is about 70-80%, and pion rejection is worse, which need further study.

Any comments and suggestions ?

Back up

SIDIS electron trigger

FAEC electron trigger				LAEC electron trigger			
Radius(cm)	E Thresho (GeV)	old J	in's cut (GeV)	Ra 90	dius(cm) - 105	P Threshol 3.0	d (GeV)
90 - 105	5.0	shE-p	reshE>4.4	10	5 - 115	3.0	
105 - 115 115 - 130	4.0 3.0	shE-p shE-p	reshE>3.5 reshE>2.6	11	.5 - 130	3.0	
130 - 150	2.0	shE-p	reshE>1.6				
150 - 200	1.0	shE>C).9				
Radius(cm) 6+1 Cluster Threshold (MeV)				Ra	idius(cm)	6+1 Cluster (MeV)	Threshold
90 - 105	990.	09	p1 E _{dep} n FCAI	90) - 105	571.5	0
105 - 115	762.	60 ⁶		1 L 1 1	15 - 115 E 120	5/1.9	
115 - 130	557.	97			.5 - 150	551.0	0
130 - 150	355.	25					
150 - 200	170.	87					11

SIDIS Electron and Pion Efficiency Curves

